

MM54HC30/MM74HC30 8-Input NAND Gate

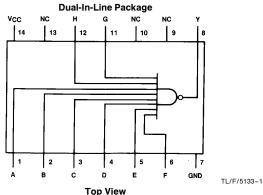
General Description

This NAND gate utilizes advanced silicon-gate CMOS technology to achieve operating speeds similar to LS-TTL gates with the low power consumption of standard CMOS integrated circuits. This device has high noise immunity and the ability to drive 10 LS-TTL loads. The 54HC/74HC logic family is functionally as well as pin-out compatible with the standard 54LS/74LS logic family. All inputs are protected from damage due to static discharge by internal diode clamps to $V_{\mbox{\footnotesize CC}}$ and ground.

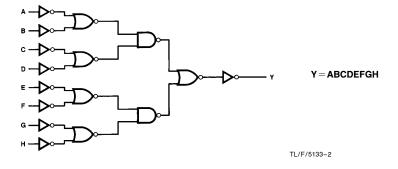
Features

- Typical propagation delay: 20 ns
- Wide power supply range: 2-6V
- Low quiescent current: 20 µA maximum (74HC Series)
- Low input current: 1 µA maximum
- Fanout of 10 LS-TTL loads

Connection and Logic Diagrams



Order Number MM54HC30 or MM74HC30



Absolute Maximum Ratings (Notes 1 & 2)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage (V _{CC})	-0.5 to $+7.0$ V
DC Input Voltage (V _{IN})	-1.5 to $V_{\rm CC} + 1.5 V_{\rm CC}$
DC Output Voltage (V _{OUT})	-0.5 to $V_{\rm CC}$ + 0.5 V
Clamp Diode Current (I _{CD})	\pm 20 mA
DC Output Current, per pin (IOUT)	\pm 25 mA
DC V _{CC} or GND Current, per pin (I _{CC})	\pm 50 mA
Storage Temperature Range (T _{STG})	-65°C to +150°C
5 5 1 1 1 (5)	

Power Dissipation (PD) (Note 3) 600 mW S.O. Package only 500 mW 260°C

Lead Temp. (T_L) (Soldering, 10 seconds)

Operating Conditions								
	Min	Max	Units					
DC Supply Voltage (V _{CC})	2	6	V					
DC Input or Output Voltage								
(V _{IN} , V _{OUT})	0	V_{CC}	V					
Operating Temp. Range (T _A)								
MM74HC	-40	+85	°C					
MM54HC	-55	+125	°C					
Input Rise/Fall Times								
(t_r, t_f) $V_{CC} = 2.0V$		1000	ns					
$V_{CC} = 4.5V$		500	ns					
$V_{CC} = 6.0V$		400	ns					

DC Electrical Characteristics (Note 4)

Symbol	Parameter	Conditions	v _{cc}	T _A = 25°C		74HC T _A = -40 to 85°C	54HC T _A = -55 to 125°C	Units
				Typ Guaranteed Limits				
V_{IH}	Minimum High Level Input Voltage		2.0V 4.5V 6.0V		1.5 3.15 4.2	1.5 3.15 4.2	1.5 3.15 4.2	V V V
V _{IL}	Maximum Low Level Input Voltage**		2.0V 4.5V 6.0V		0.5 1.35 1.8	0.5 1.35 1.8	0.5 1.35 1.8	V V V
V _{OH}	Minimum High Level Output Voltage	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $ I_{OUT} \le 20 \mu A$	2.0V 4.5V 6.0V	2.0 4.5 6.0	1.9 4.4 5.9	1.9 4.4 5.9	1.9 4.4 5.9	V V V
		$V_{IN} = V_{IH} \text{ or } V_{IL}$ $ I_{OUT} \le 4.0 \text{ mA}$ $ I_{OUT} \le 5.2 \text{ mA}$	4.5V 6.0V	4.2 5.7	3.98 5.48	3.84 5.34	3.7 5.2	V V
V _{OL}	Maximum Low Level Output Voltage	$V_{IN} = V_{IH}$ $ I_{OUT} \le 20 \mu A$	2.0V 4.5V 6.0V	0 0 0	0.1 0.1 0.1	0.1 0.1 0.1	0.1 0.1 0.1	V V V
		$V_{IN} = V_{IH}$ $ I_{OUT} \le 4 \text{ mA}$ $ I_{OUT} \le 5.2 \text{ mA}$	4.5V 6.0V	0.2 0.2	0.26 0.26	0.33 0.33	0.4 0.4	V V
I _{IN}	Maximum Input Current	V _{IN} =V _{CC} or GND	6.0V		±0.1	±1.0	±1.0	μΑ
I _{CC}	Maximum Quiescent Supply Current	$V_{IN} = V_{CC}$ or GND $I_{OUT} = 0 \mu A$	6.0V		2.0	20	40	μΑ

Note 1: Maximum Ratings are those values beyond which damage to the device may occur.

Note 2: Unless otherwise specified all voltages are referenced to ground.

Note 3: Power Dissipation temperature derating — plastic "N" package: -12 mW/°C from 65°C to 85°C; ceramic "J" package: -12 mW/°C from 100°C to 125°C.

Note 4: For a power supply of 5V \pm 10% the worst case output voltages (V_{OH}, and V_{OL}) occur for HC at 4.5V. Thus the 4.5V values should be used when designing with this supply. Worst case V_{IH} and V_{IL} occur at V_{CC}=5.5V and 4.5V respectively. (The V_{IH} value at 5.5V is 3.85V.) The worst case leakage current (I_{IN}, I_{CC}, and I_{OZ}) occur for CMOS at the higher voltage and so the 6.0V values should be used.

^{**}V_{IL} limits are currently tested at 20% of V_{CC}. The above V_{IL} specification (30% of V_{CC}) will be implemented no later than Q1, CY'89.

AC Electrical Characteristics $v_{CC}\!=\!5\text{V},\,T_{A}\!=\!25^{\circ}\text{C},\,C_{L}\!=\!15\,\text{pF},\,t_{r}\!=\!t_{f}\!=\!6\,\text{ns}$

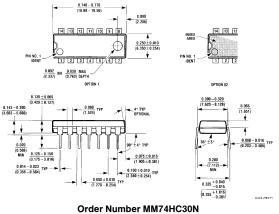
Symbol	Parameter	Conditions	Тур	Guaranteed Limit	Units
t _{PHL} , t _{PLH}	Maximum Propagation Delay		20	30	ns

$\textbf{AC Electrical Characteristics} \ \ V_{CC} = 2.0V \ \text{to 6.0V}, \ C_L = 50 \ \text{pF}, \ t_r = t_f = 6 \text{tns (unless otherwise specified)}$

Symbol	Parameter	Conditions	v _{cc}	T _A =25°C		74HC T _A = -40 to 85°C	54HC T _A = -55 to 125°C	Units
				Typ Guaranteed Limits			Limits	
t _{PHL} , t _{PLH}	Maximum Propagation Delay		2.0V 4.5V 6.0V	66 23 18	160 35 30	190 42 36	220 49 42	ns ns ns
t _{TLH} , t _{THL}	Maximum Output Rise and Fall Time		2.0V 4.5V 6.0V	30 8 7	75 15 13	95 19 16	110 22 19	ns ns ns
C _{PD}	Power Dissipation Capacitance (Note 5)			34				pF
C _{IN}	Maximum Input Capacitance			5	10	10	10	pF

Note 5: C_{PD} determines the no load dynamic power consumption, $P_D = C_{PD} \ V_{CC}^2 \ f + I_{CC} \ V_{CC}$, and the no load dynamic current consumption, $I_S = C_{PD} \ V_{CC} \ f + I_{CC}$.

Physical Dimensions inches (millimeters) 0.785 (19.939) MAX 14 13 12 11 10 9 8 0 025 (0.635) RAD 0.220-0.310 (5.588-7.874) 1 2 3 4 5 6 7 0.290-0.320 (7.366-8.128) 0.060 ±0.005 (5.080) MAX (1.524 ±0.127) (0.508-1.524) 10° MAX 0.008-0.012 0.310-0.410 0.125-0.200 0.098 (0.457 ±0.076) (2.489) MAX BOTH ENDS (3.175-5.080) 0.100 ±0.010 (3.81) MIN J14A (REV G) Order Number MM54HC30J or MM74HC30J NS Package J14A 0.749 - 0.770 (18.80 - 19.56)



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NS Package N14A

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